

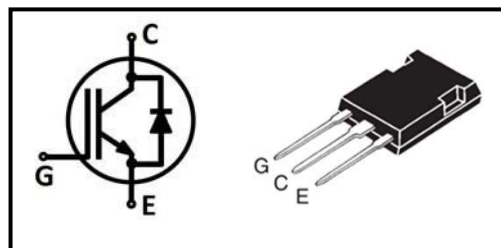
特征/Features

- 饱和压降为正温度系数，易于并联使用
Easy parallel switching capability due to positive temperature coefficient in V_{CEsat}
- 内置快速恢复二极管
Built-in fast recovery diode
- 高可靠性及热稳定性，良好的参数一致性
High reliability and thermal stability, good parameter consistency

型号/Type	打标/Marking	封装/Package
QM50N120B	QM50N120B	TO-247-3L Plus

应用领域/Applications

- 太阳能逆变器/Solar Inverter
- 不间断电源/UPS
- 焊接/Welding



最大额定值/Maximum Rated Values

Item	Symbol	Value	Unit
集电极-发射极电压 Collector-emitter voltage	V_{CE}	1200	V
集电极电流 DC collector current, limited by T_{vjmax} $T_C=25^\circ C$ $T_C=130^\circ C$	I_C	100 50	A
集电极脉冲电流 Pulsed collector current, t_p limited by T_{jmax1}	I_{Cpuls}	200	
关闭安全操作区域 Turn off safe operating area $V_{CE} \leq 1200V$, $T_{vj} \leq 175^\circ C$, $t_p = 1\mu s$		200	
二极管正向电流 Diode forward current, limited by T_{jmax} $T_C=25^\circ C$ $T_C=100^\circ C$	I_F	100 50	
二极管脉冲电流 Diode pulsed current, t_p limited by T_{jmax1}	I_{Fpuls}	200	V
栅极-发射极电压 Gate-emitter voltage	V_{GE}	± 20	
瞬态栅极-发射极电压 Transient Gate-emitter voltage ($t_p \leq 10\mu s, D < 0.01$)		± 30	
耗散功率 Power dissipation $T_C=25^\circ C$ $T_C=100^\circ C$	P_{tot}	600	W
		160	
工作结温 Operating junction temperature	T_j	-40~175	°C
储存温度 Storage temperature	T_{stg}	-55~150	
焊接温度 Soldering temperature, wave soldering 1.6mm (0.063in.) from case for 10s		260	

1) Defined by design. Not subject to production test.

电学特性/Electrical Characteristics

静态特性/Static Characteristics (at $T_j=25^\circ\text{C}$ unless otherwise specified)

Item	Symbol	Conditions	Min.	Typ.	Max.	Unit
集电极-发射极击穿电压 Collector-emitter breakdown voltage	$V_{(BR)CES}$	$V_{GE}=0V,$ $I_C=0.25mA$	1200	-	-	V
集电极-发射极饱和电压 Collector-emitter saturation voltage	$V_{CE(sat)}$	$V_{GE}=15V, I_C=50A$ $T_j=25^\circ\text{C}$	-	1.8	2.3	
		$T_j=150^\circ\text{C}$	-	2.35	-	
		$T_j=175^\circ\text{C}$	-	2.50	-	
二极管正向压降 Diode forward voltage	V_F	$V_{GE}=0V, I_F=50A$ $T_j=25^\circ\text{C}$	-	2.0	-	
		$T_j=150^\circ\text{C}$	-	1.8	-	
		$T_j=175^\circ\text{C}$	-	1.7	-	
阈值电压 G-E threshold voltage	$V_{GE(th)}$	$I_C=1.7mA,$ $V_{CE}=V_{GE}$	5.2	5.8	6.4	
集电极-发射极漏电流 C-E leakage current	I_{CES}	$V_{CE}=1200V,$ $V_{GE}=0V$ $T_j=25^\circ\text{C}$	-	-	0.01	mA
		$T_j=175^\circ\text{C}$	-	-	4.0	
栅极-发射极漏电流 G-E leakage current	I_{GES}	$V_{CE}=0V,$ $V_{GE}=20V$	-	-	100	nA

动态特性/Dynamic Characteristics

Item	Symbol	Conditions	Min.	Typ.	Max.	Unit
输入电容 Input capacitance	C_{iss}	$V_{CE}=25V,$ $V_{GE}=0V,$ $f=1MHz$	-	6050	-	pF
输出电容 Output capacitance	C_{oss}		-	145	-	
反馈电容 Reverse transfer capacitance	C_{rss}		-	135	-	
栅电荷 Gate charge	Q_G	$V_{CC}=960V, I_C=50A,$ $V_{GE}=15V$	-	516	-	nC

热学特性/Thermal Characteristics

Item	Symbol	Conditions	Min.	Typ.	Max.	Unit
结-外壳热阻 IGBT thermal resistance, junction-case	R_{thJC}	-	-	-	0.25	K/W
二极管结-外壳热阻 Diode thermal resistance, junction-case	R_{thJCD}	-	-	-	0.48	
结-环境热阻 Thermal Resistance, junction-ambient	R_{thJA}	-	-	-	40	

IGBT开关特性(感性负载)/IGBT Switching Characteristics

Item	Symbol	Conditions	Min.	Typ.	Max.	Unit	
开通延迟时间 Turn-on delay time	$t_{d(on)}$	$T_j=25^{\circ}C,$ $V_{CC}=600V,$ $I_C=50A,$ $V_{GE}=0/15V,$ $R_G=10\Omega,$ <i>Inductive load</i>	-	96	-	ns	
上升时间 Rise time	t_r		-	121	-		
关断延迟时间 Turn-off delay time	$t_{d(off)}$		-	575	-		
下降时间 Fall time	t_f			-	39	-	
开通损耗 Turn-on energy	E_{on}			-	5.50	-	mJ
关断损耗 Turn-off energy	E_{off}			-	3.21	-	
开关损耗 Total switching energy	E_{ts}			-	8.71	-	
开通延迟时间 Turn-on delay time	$t_{d(on)}$		$T_j=175^{\circ}C,$ $V_{CC}=600V,$ $I_C=50A,$ $V_{GE}=0/15V,$ $R_G=10\Omega,$ <i>Inductive load</i>	-	90	-	ns
上升时间 Rise time	t_r			-	135	-	
关断延迟时间 Turn-off delay time	$t_{d(off)}$	-		655	-		
下降时间 Fall time	t_f			-	82	-	
开通损耗 Turn-on energy	E_{on}			-	5.90	-	mJ
关断损耗 Turn-off energy	E_{off}			-	4.23	-	
开关损耗 Total switching energy	E_{ts}			-	10.13	-	

二极管开关特性/Diode Characteristics

Item	Symbol	Conditions	Min.	Typ.	Max.	Unit
反向恢复时间 Diode reverse recovery time	t_{rr}	$T_j=25^{\circ}C,$ $V_R=600V,$ $I_F=50A,$ $di_F/dt=400A/\mu s$	-	233	-	ns
反向恢复电荷 Diode reverse recovery charge	Q_{rr}		-	2.76	-	μC
反向恢复峰值电流 Diode peak reverse recovery current	I_{rrm}		-	18.8	-	A
反向恢复时间 Diode reverse recovery time	t_{rr}	$T_j=175^{\circ}C,$ $V_R=600V,$ $I_F=50A,$ $di_F/dt=400A/\mu s$	-	465	-	ns
反向恢复电荷 Diode reverse recovery charge	Q_{rr}		-	9.82	-	μC
反向恢复峰值电流 Diode peak reverse recovery current	I_{rrm}		-	44.0	-	A

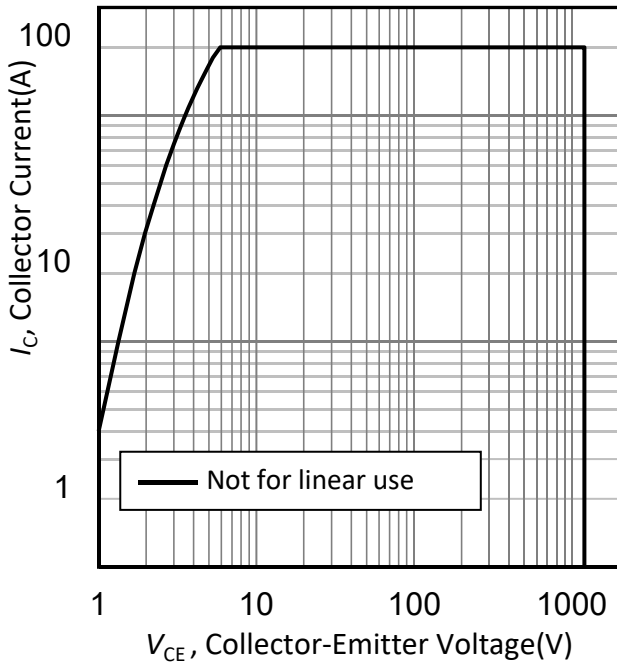


Figure 1. 正向偏置安全工作区/Forward bias safe operating area ($D=0, T_C=25^\circ\text{C}, T_{vj}\leq 175^\circ\text{C}, V_{GE}=15\text{V}$)

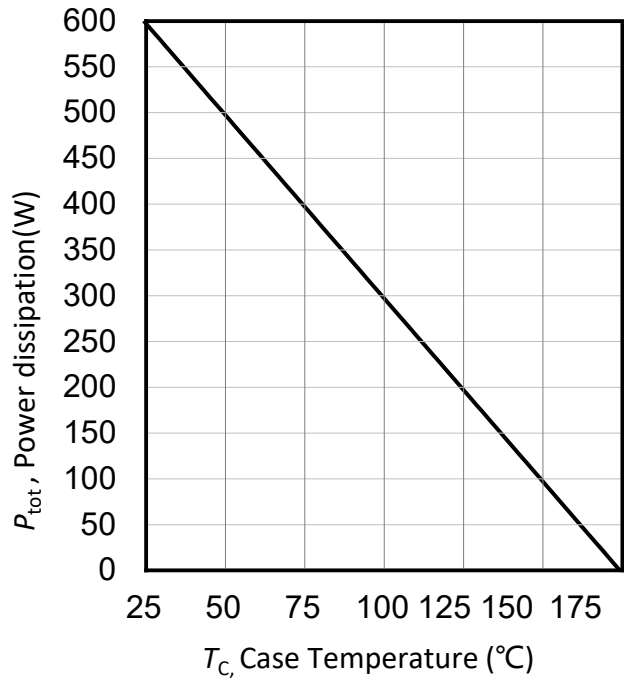


Figure 2. 功耗与外壳温度的关系/Power dissipation as a function of case temperature ($T_{vj}\leq 175^\circ\text{C}$)

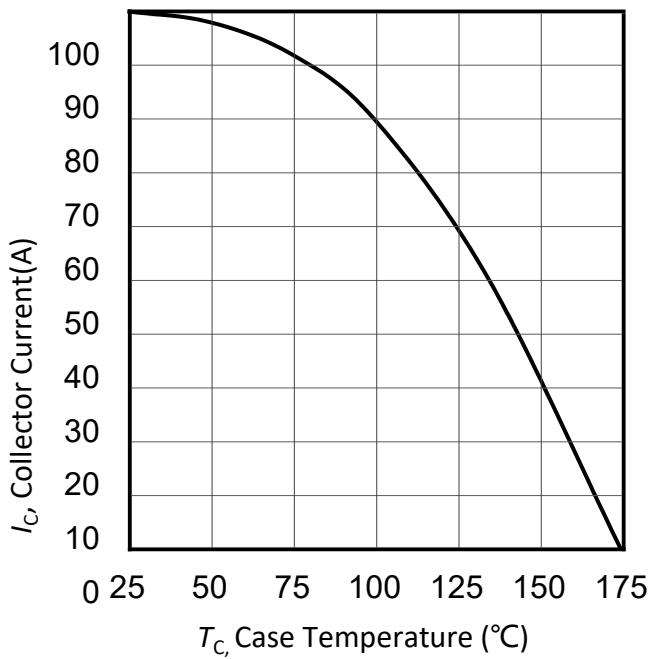


Figure 3. 集电极电流与外壳温度的关系 /Collector current as a function of case temperature ($T_{vj}\leq 175^\circ\text{C}, V_{GE}\geq 15\text{V}$)

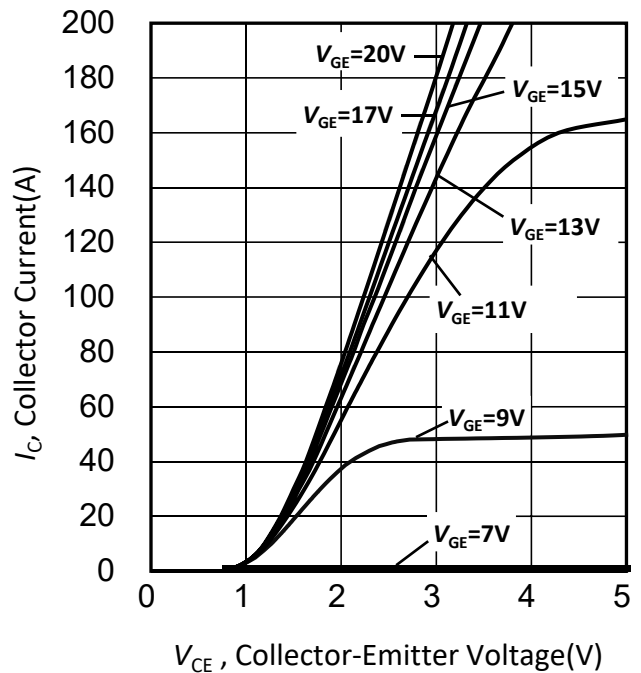


Figure 4. 典型输出特性/Typical output characteristic ($T_{vj}=25^\circ\text{C}$)

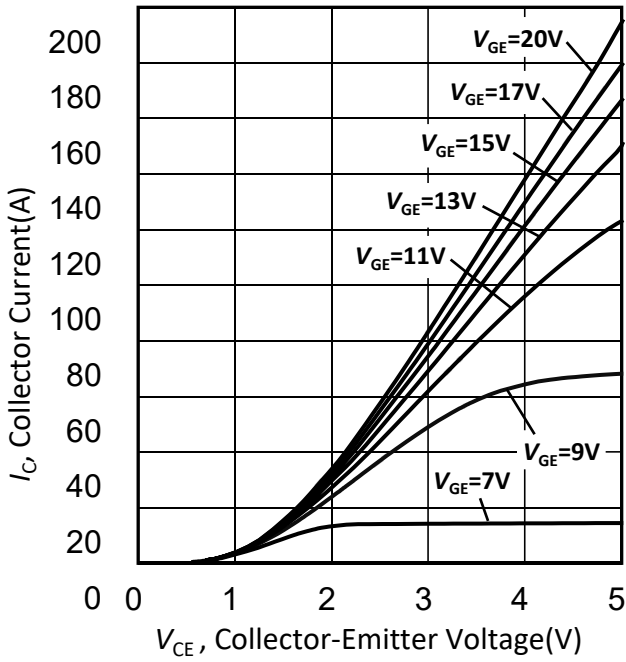


Figure 5. 典型输出特性/Typical output characteristic
($T_{vj}=175^{\circ}\text{C}$)

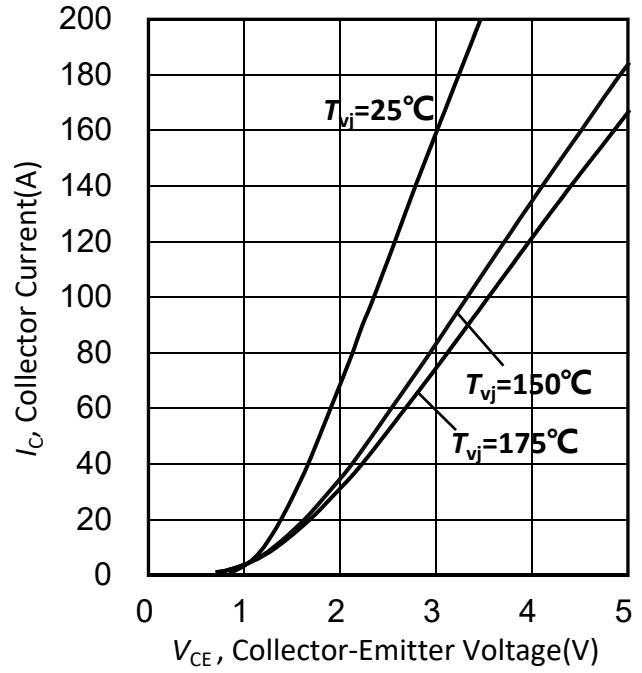


Figure 6. 集电极-发射极饱和电压特性
/Collector-emitter saturation voltage characteristic
($V_{GE}=15\text{V}$)

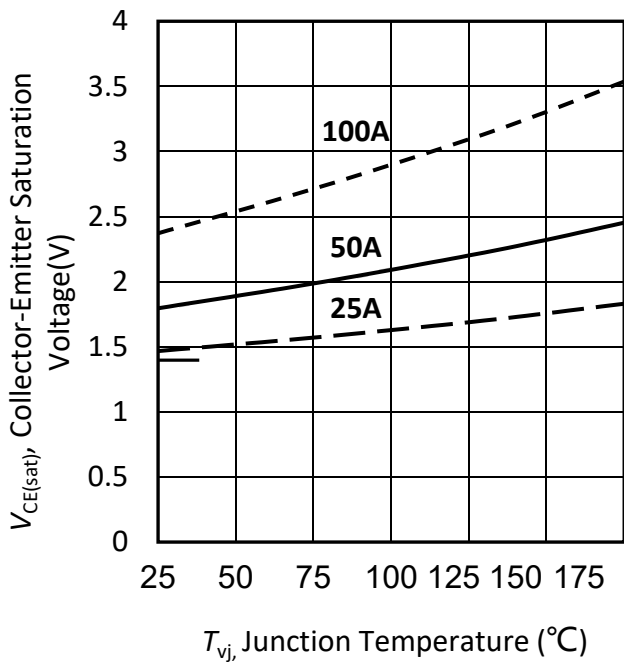


Figure 7. 典型集电极-发射极饱和电压与结温的关系
/Typical collector-emitter saturation voltage as a function of junction temperature
($V_{GE}=15\text{V}$)

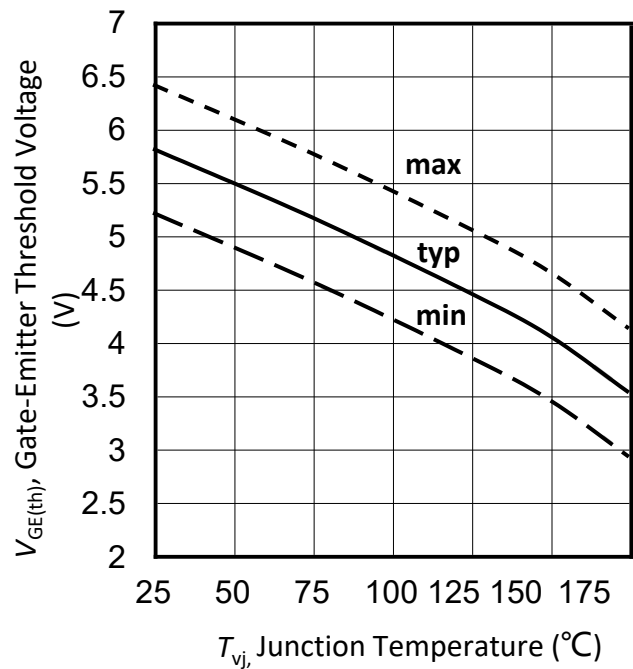


Figure 8. 栅极-发射极阈值电压与结温的关系
/Gate-emitter threshold voltage as a function of junction temperature
($I_C=1.7\text{mA}$)

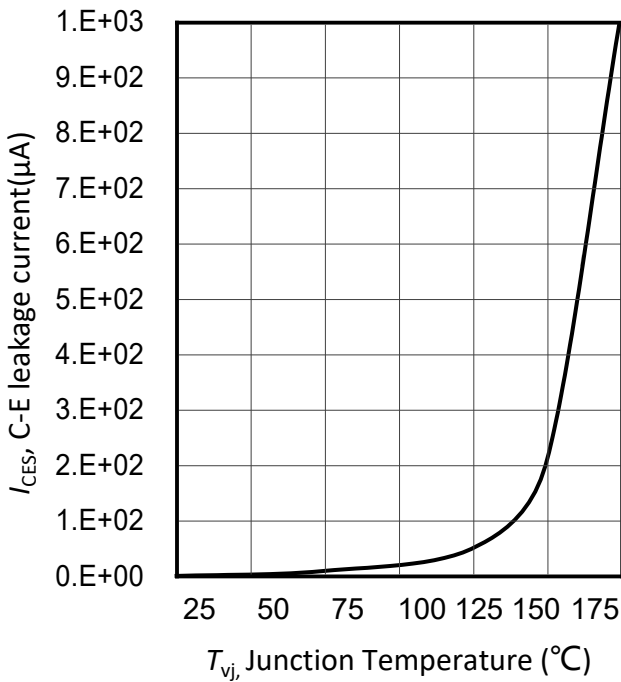


Figure 9. 典型 I_{CES} 漏电流作为结温的函数
/Typical I_{CES} leakage current
as a function of junction temperature
($V_{CE}=1200V$, $V_{GE}=0V$)

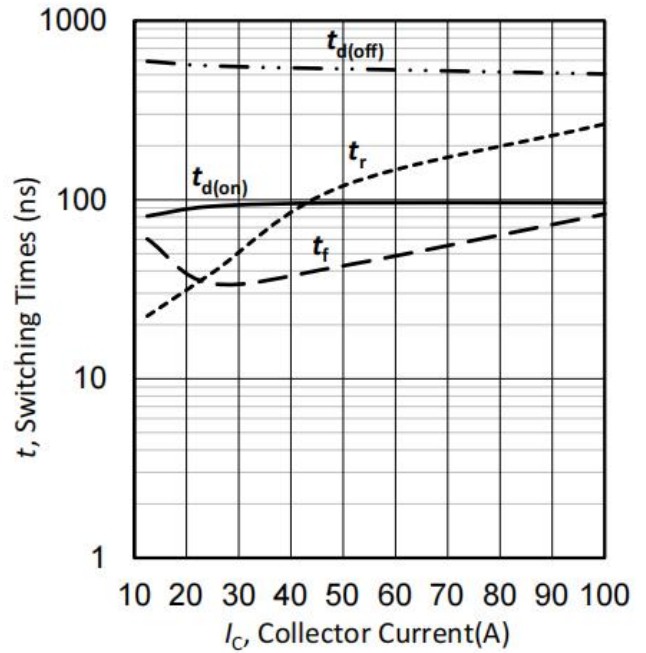


Figure 10. 典型开关时间与集电极电流的关系
/Typical switching times as a function of collector current
(inductive load, $T_{vj}=25^{\circ}C$,
 $V_{CE}=600V$, $V_{GE}=0/15V$, $R_G=10\Omega$)

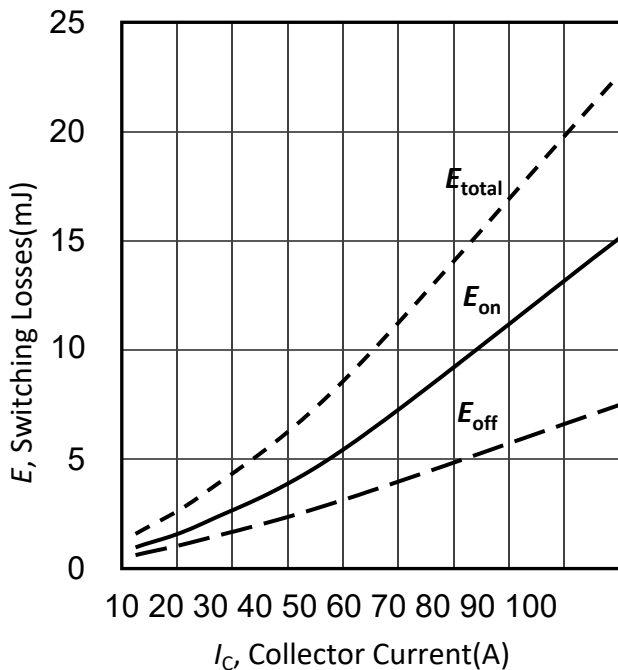


Figure 11. 典型开关能量损耗与集电极电流的关系
/Typical switching energy losses as a function of collector current
(inductive load, $T_{vj}=25^{\circ}C$,
 $V_{CE}=600V$, $V_{GE}=0/15V$, $R_G=10\Omega$)

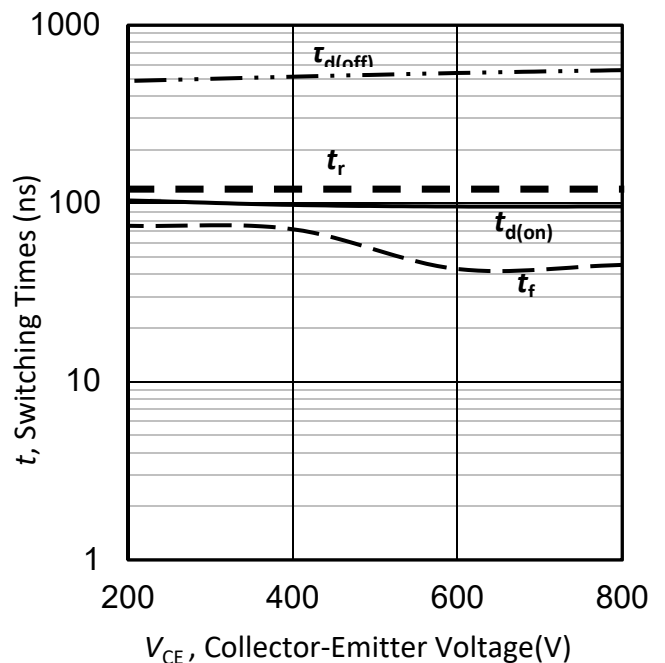


Figure 12. 典型开关时间与集电极发射极电压的关系
/Typical switching times as a function of collector emitter voltage
(inductive load, $T_{vj}=25^{\circ}C$,
 $I_C=50A$, $V_{GE}=0/15V$, $R_G=10\Omega$)

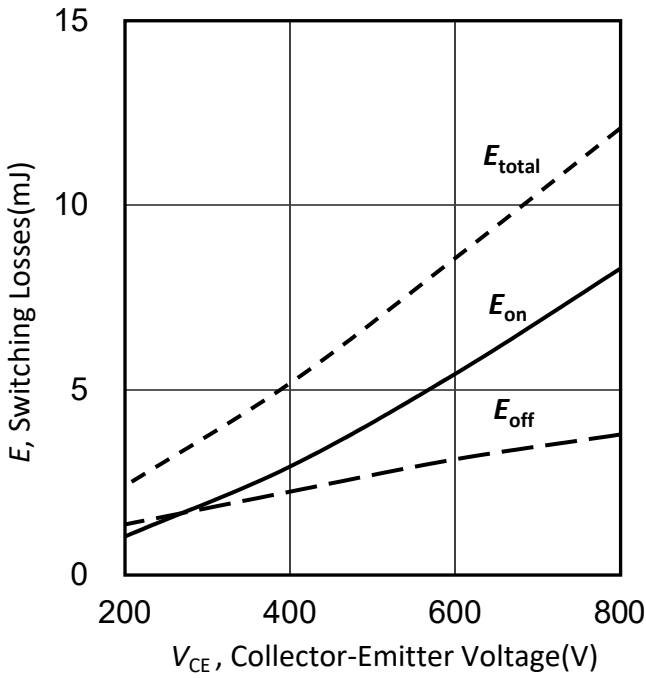


Figure 13. 典型开关能量损耗与集电极发射极电压的关系/Typical switching energy losses as a function of collector emitter voltage (inductive load, $T_{vj}=25^{\circ}\text{C}$, $I_C=50\text{A}$, $V_{GE}=0/15\text{V}$, $R_G=10\Omega$)

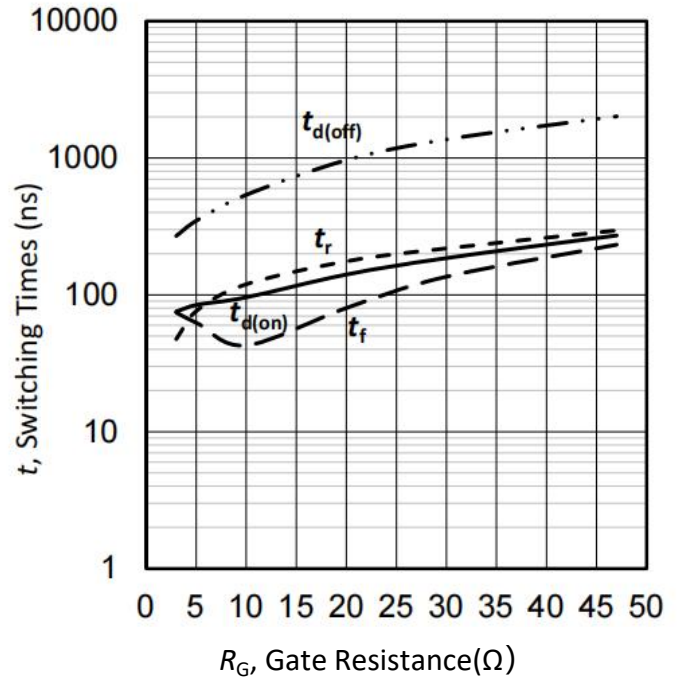


Figure 14. 典型开关时间与栅极电阻器的关系 /Typical switching times as a function of gate resistor(inductive load, $T_{vj}=25^{\circ}\text{C}$, $V_{CE}=600\text{V}$, $V_{GE}=0/15\text{V}$, $I_C=50\text{A}$)

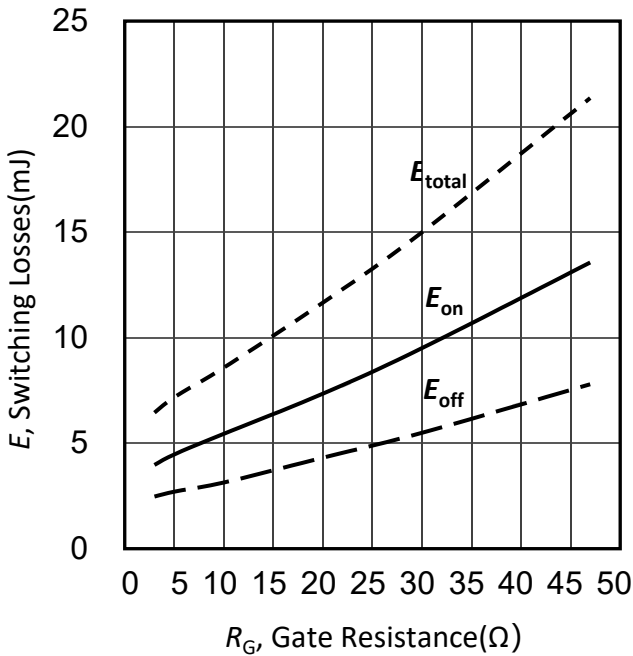


Figure 15. 典型开关能量损耗与栅极电阻器的关系 /Typical switching energy losses as a function of gate resistor(inductive load, $T_{vj}=25^{\circ}\text{C}$, $V_{CE}=600\text{V}$, $V_{GE}=0/15\text{V}$, $I_C=50\text{A}$)

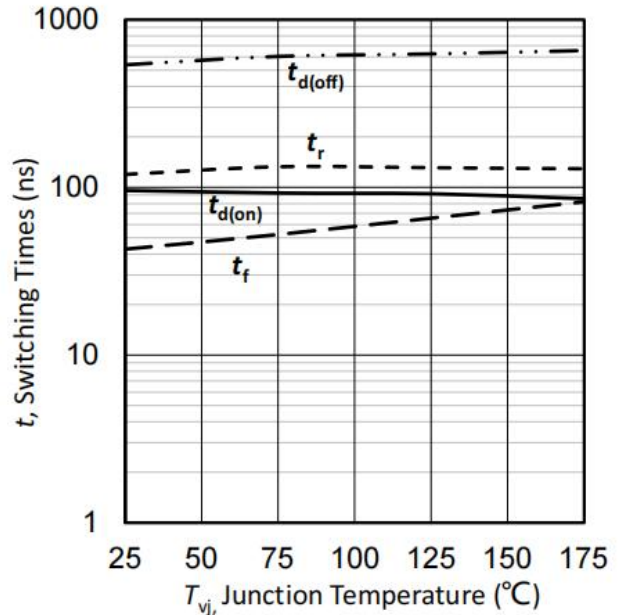


Figure 16. 典型开关时间与结温的关系/Typical switching times as a function of junction temperature (inductive load, $V_{CE}=600\text{V}$, $V_{GE}=0/15\text{V}$, $I_C=50\text{A}$, $R_G=10\Omega$)

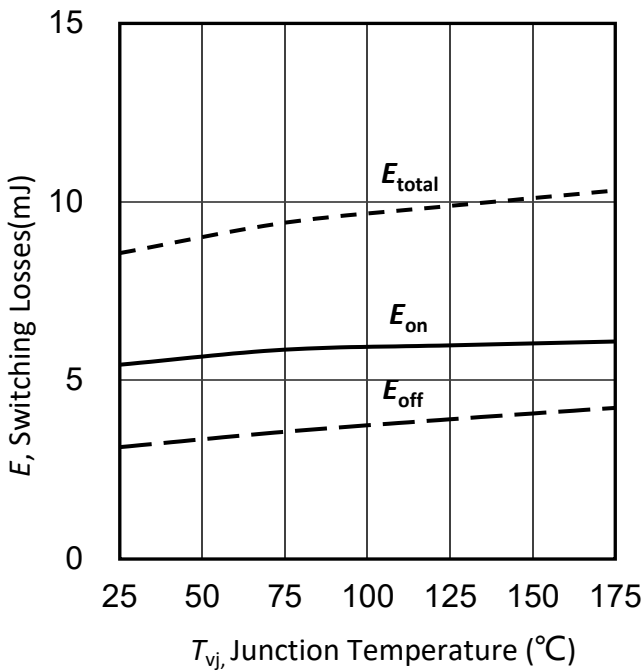


Figure 17. 典型开关能量损耗与结温的关系
 /Typical switching energy losses as a function of junction temperature
 (inductive load, $V_{CE}=600V$, $V_{GE}=0/15V$, $I_C=50A$, $R_G=10\Omega$)

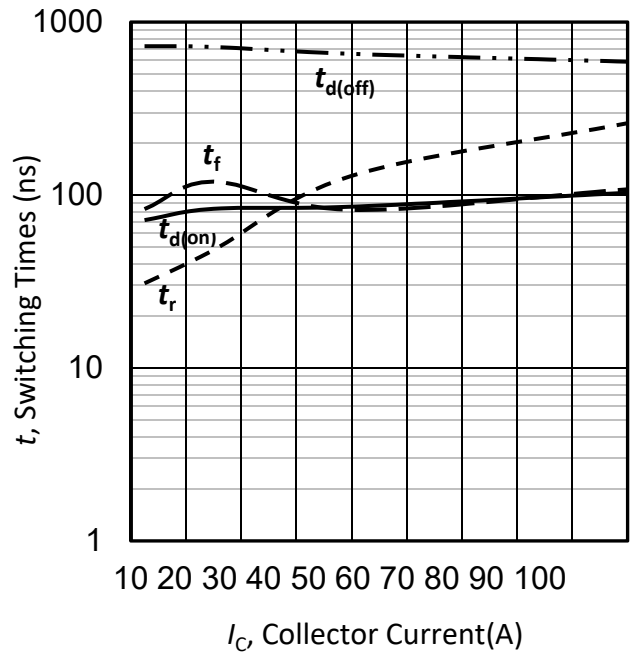


Figure 18. 典型开关时间与集电极电流的关系
 /Typical switching times as a function of collector current
 (inductive load, $T_{vj}=175^\circ C$, $V_{CE}=600V$, $V_{GE}=0/15V$, $R_G=10\Omega$)

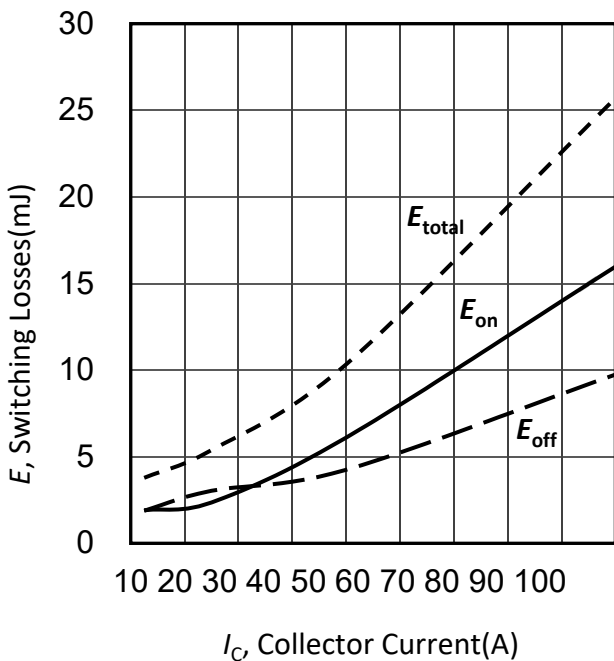


Figure 19. 典型开关能量损耗与集电极电流的关系
 Typical switching energy losses as a function of collector current
 (inductive load, $T_{vj}=175^\circ C$, $V_{CE}=600V$, $V_{GE}=0/15V$, $R_G=10\Omega$)

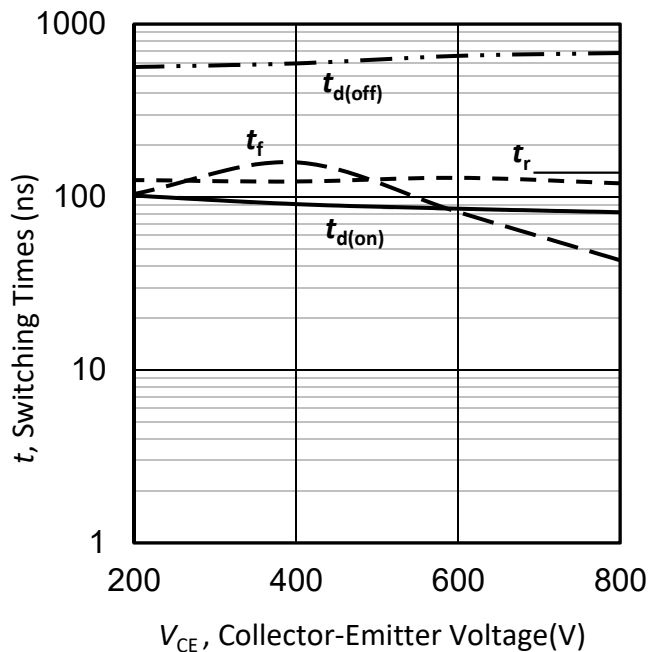


Figure 20. 典型开关时间与集电极发射极电压的关系
 /Typical switching times as a function of collector emitter voltage
 (inductive load, $T_{vj}=175^\circ C$, $I_C=50A$, $V_{GE}=0/15V$, $R_G=10\Omega$)

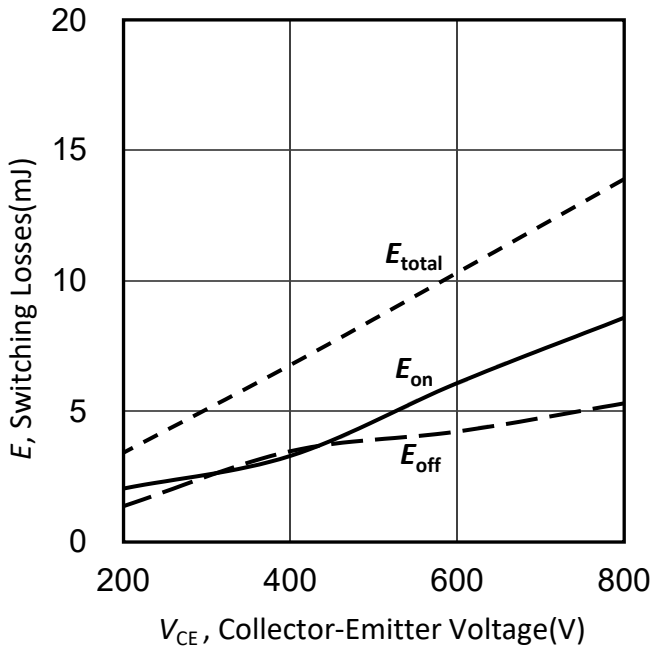


Figure 21. 典型开关能量损耗与集电极发射极电压的关系 / Typical switching energy losses as a function of collector emitter voltage
(inductive load, $T_{vj}=175^{\circ}\text{C}$, $I_C=50\text{A}$, $V_{GE}=0/15\text{V}$, $R_G=10\Omega$)

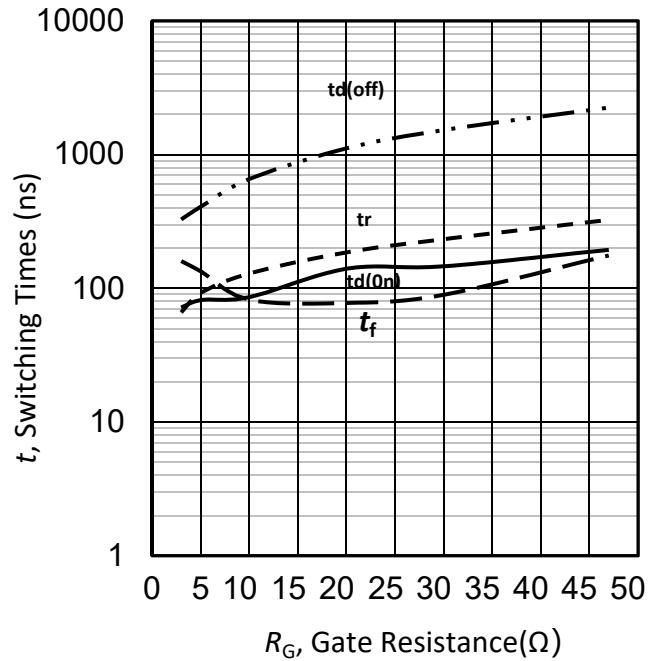


Figure 22. 典型开关时间与栅极电阻器的关系 / Typical switching times as a function of gate resistor
(inductive load, $T_{vj}=175^{\circ}\text{C}$, $V_{CE}=600\text{V}$, $V_{GE}=0/15\text{V}$, $I_C=50\text{A}$)

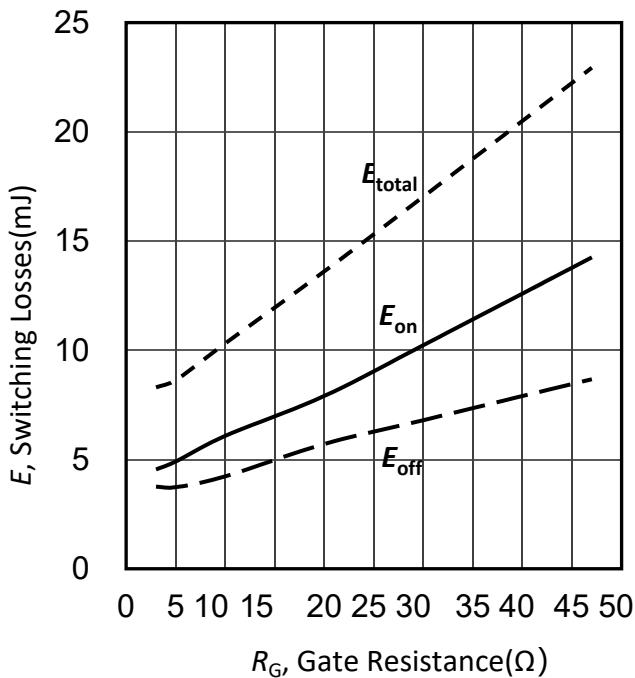


Figure 23. 典型开关能量损耗与栅极电阻器的关系 / Typical switching energy losses as a function of gate resistor
(inductive load, $T_{vj}=175^{\circ}\text{C}$, $V_{CE}=600\text{V}$, $V_{GE}=0/15\text{V}$, $I_C=50\text{A}$)

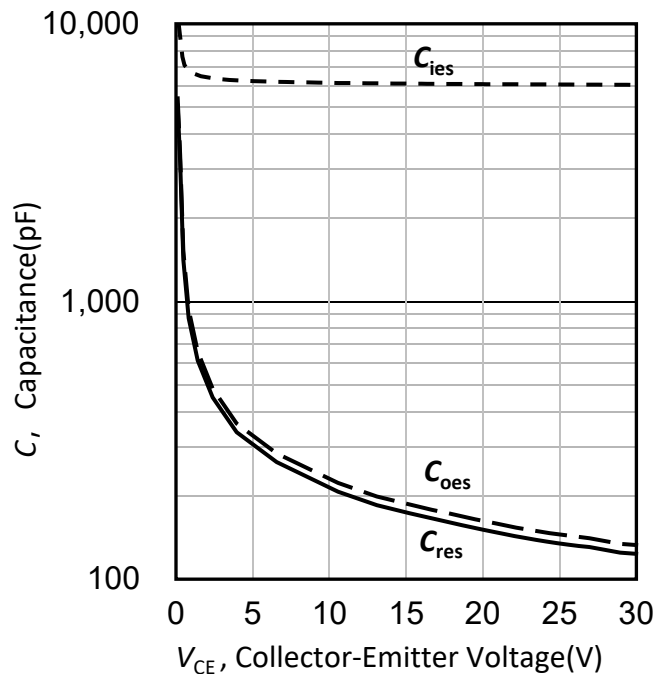


Figure 24. 典型电容与集电极-发射极电压的关系 / Typical capacitance as a function of collector-emitter voltage

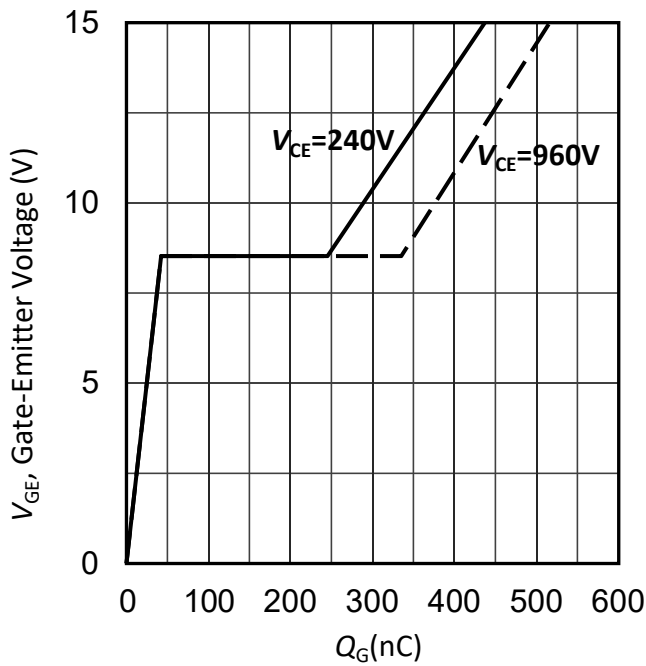


Figure 25. 典型栅极电荷
/Typical gate charge
($I_C=50A$)

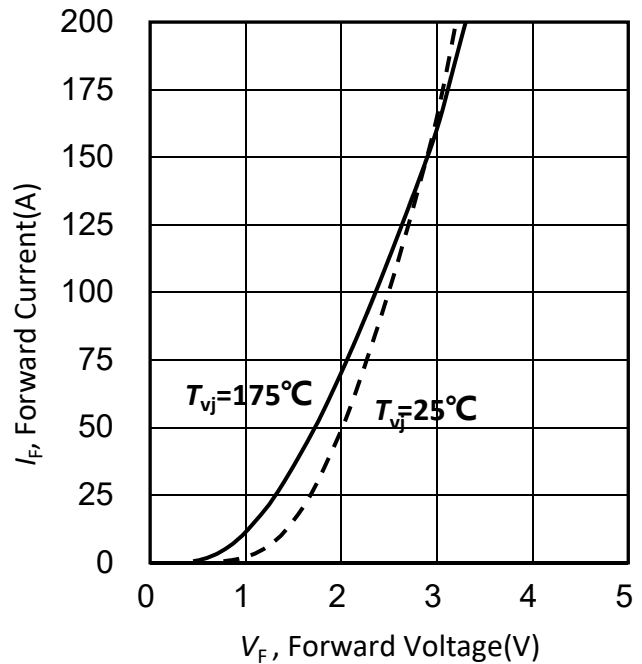


Figure 26. 典型二极管正向电流与正向电压的
函数关系/Typical diode forward
current as a function of forward
voltage

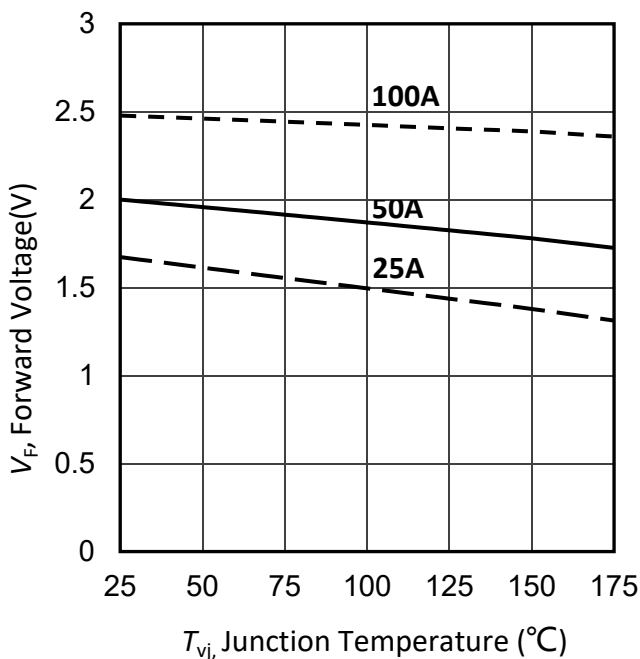


Figure 27. 典型二极管正向电压与结温的关系
/Typical diode forward voltage as
a function of junction temperature

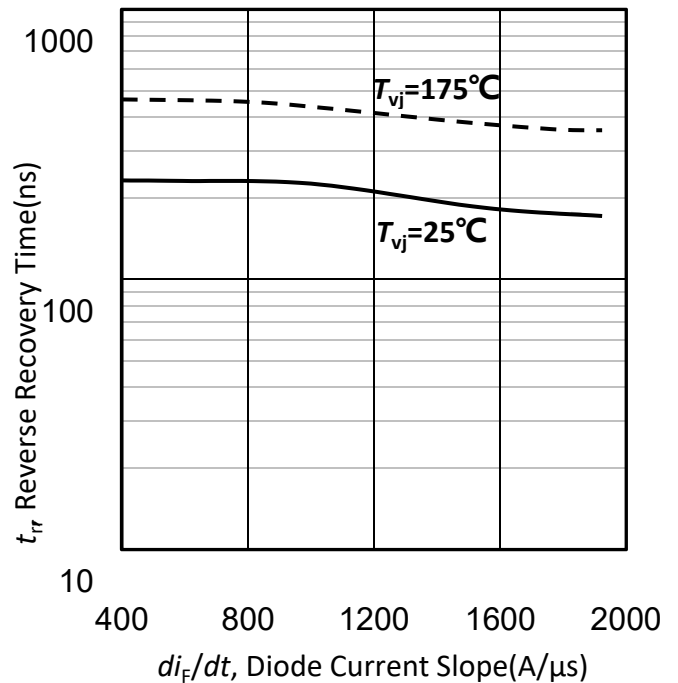


Figure 28. 典型反向恢复时间与二极管电流斜
率的关系/Typical reverse
recovery time as a function of
diode current slope ($V_R=600V$)

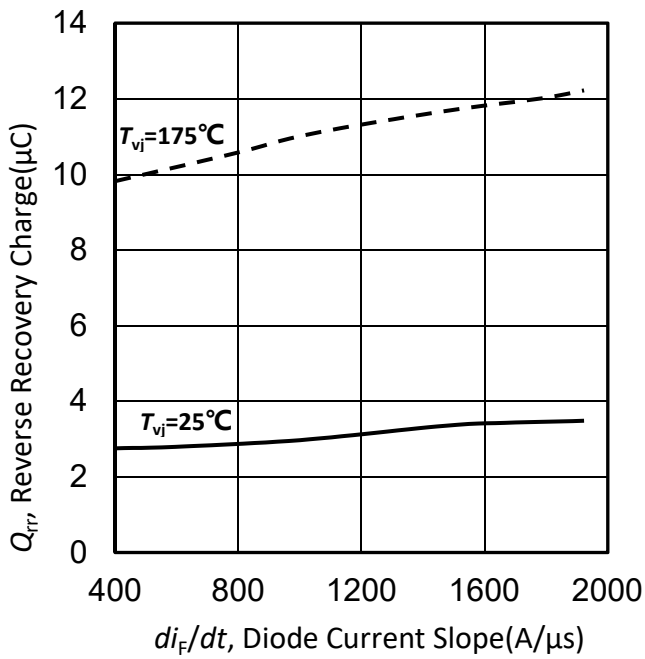


Figure 29. 典型反向恢复电荷与二极管电流斜率的关系/Typical reverse recovery charge as a function of diode current slope ($V_R=600V$)

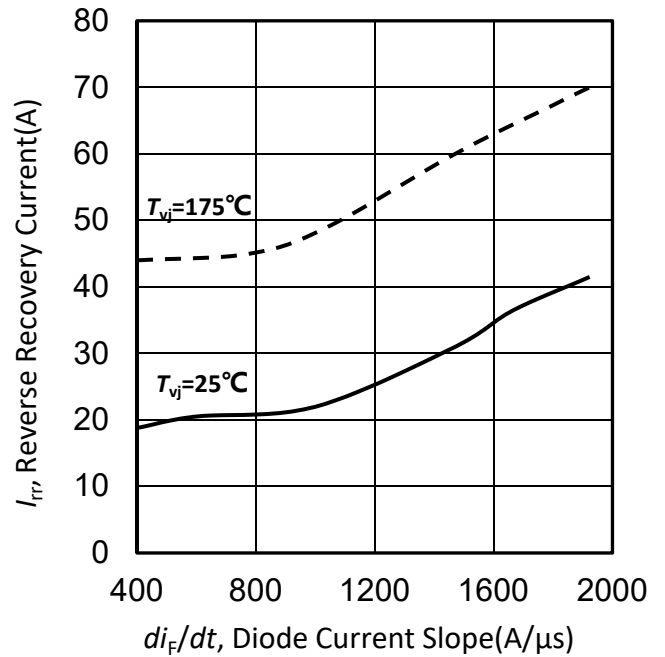
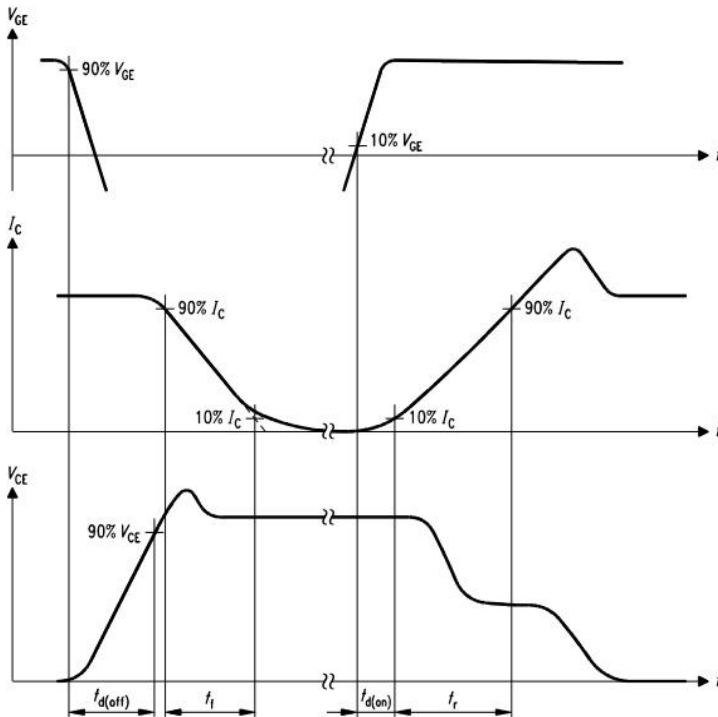
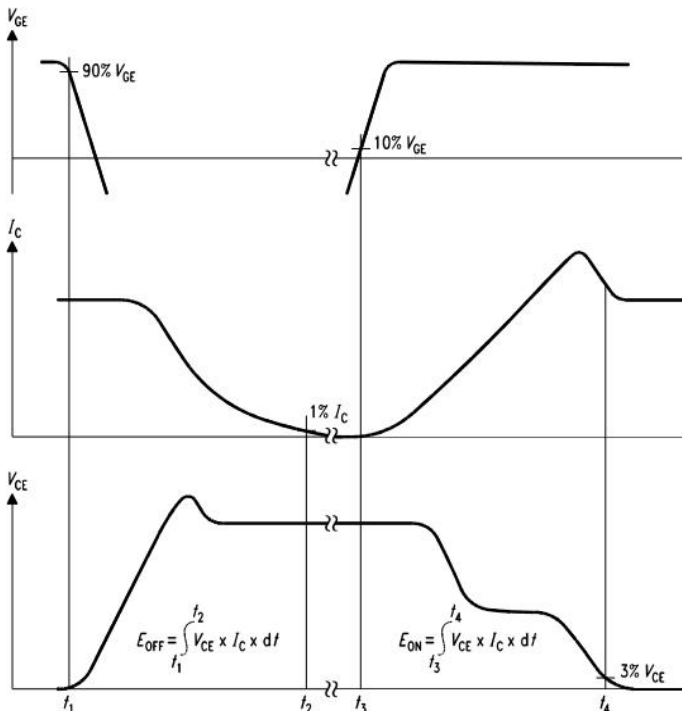


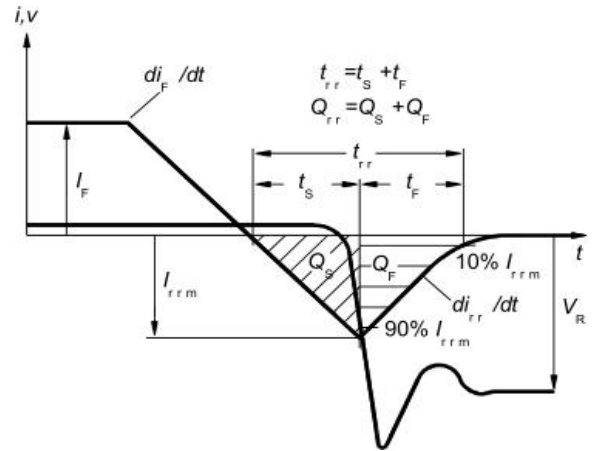
Figure 30. 典型反向恢复电流与二极管电流斜率的关系/Typical reverse recovery current as a function of diode current slope ($V_R=600V$)



**Figure A. 开关时间的定义/
Definition of switching times**



**Figure B. 开关损耗的定义/
Definition of switching losses**



**Figure C. 二极管开关特性的定义
/Definition of diodes switching characteristics**

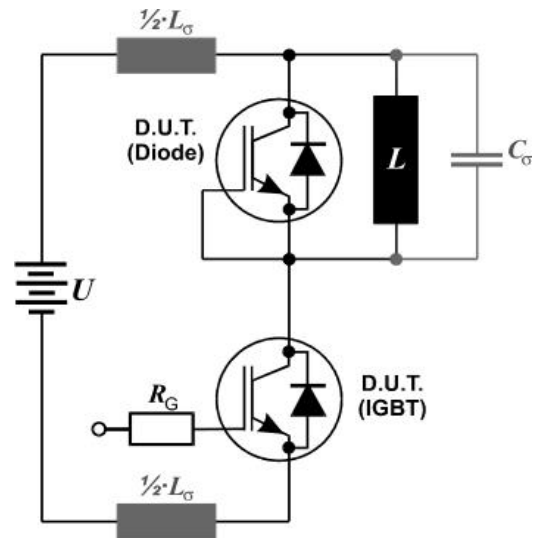
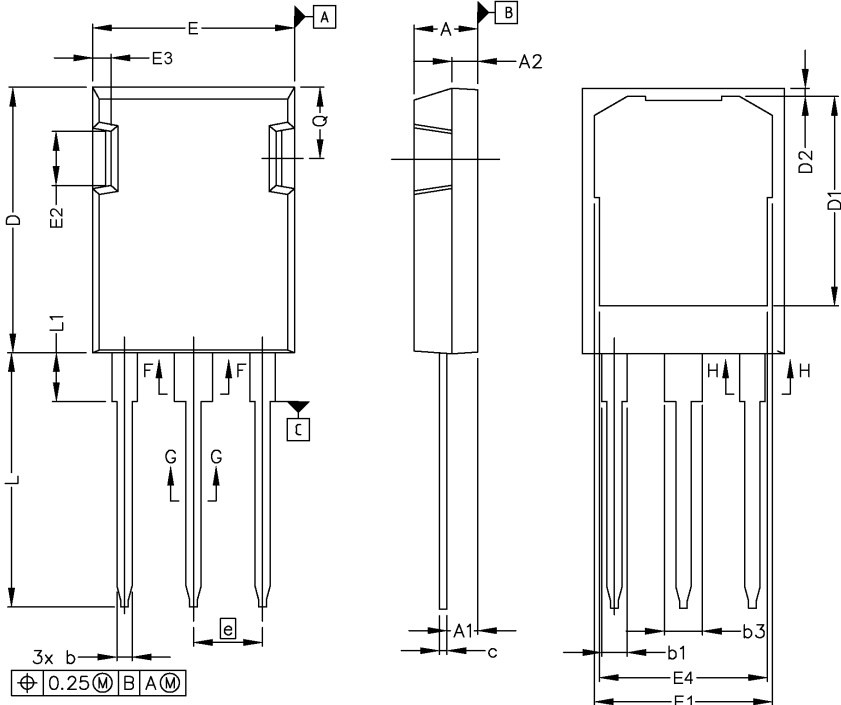


Figure D. 开关测试电路/Switching test circuit

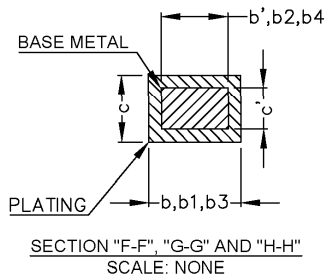
TO-247-3L Plus



SYMBOL	MIN	MAX
A	4.83	5.21
A1	2.29	2.54
A2	1.91	2.16
b'	1.07	1.28
b	1.07	1.33
b1	1.91	2.41
b2	1.91	2.16
b3	2.87	3.38
b4	2.87	3.13
c'	0.55	0.65
c	0.55	0.68
D	20.80	21.10
D1	16.25	17.65
D2	0.50	0.80
E	15.75	16.13
E1	13.10	14.15
E2	3.68	5.10
E3	1.00	1.90
E4	12.38	13.43
e	5.44 BSC	
N	3	
L	19.81	20.32
L1	3.70	4.00
Q	5.49	6.00

NOTE:
 1. ALL METAL SURFACES: TIN PLATED, EXCEPT AREA OF CUT
 2. DIMENSIONING & TOLERANCEING CONFIRM TO ASME Y14.5M-1994.
 3. ALL DIMENSIONS ARE IN MILLIMETERS. ANGLES ARE IN DEGREES.
 4. THIS DRAWING WILL MEET ALL DIMENSIONS REQUIREMENT OF JEDEC outlines TO-247 AD.

- 1 - GATE
- 2 - DRAIN (COLLECTOR)
- 3 - SOURCE (EMITTER)
- 4 - DRAIN (COLLECTOR)



修订历史/Revision History:

修订 /Revision	主题（自上次修订以来的主要变化） /Subjects (major changes since last revision)	日期 /Date
1.0	Initial Version	2023-01
2.0	Update the English and Chinese versions	2023-04

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